

Morphological Characterization of SEM Thin Silver Films Using Thresholding

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Abstract : Thin Silver films given the great well-developed in the materials science and characterization technologies are in high requirement, given the wide-spread use of coatings in many engineering and science fields. In this paper, we report a simple image thresholding method to segment and to distinguish the pores from solid of thin Silver films prepared by electroless-plating deposition method at various plating times. This approach aims to analyze the detected pores on the surface of the studied samples by measuring their porosity, pores size and their distribution

Keywords : binary image, Image processing, image thresholding, Porosity, segmentation, SEM image, thin silver film